Base form
$$X \sim f$$

$$f(x) = \sum_{k=1}^{K} \omega_k g_k(x|\theta_k)$$
with
$$\sum_{k=1}^{K} \omega_k = 1$$

Hierarchical representation

$$X|C \sim g_c$$

$$C \sim Pr(C = k) = \omega_k$$

$$p(x) = \sum_{k=1}^{K} p(x|C = k)p(C = k)$$

Observed data likelihood

$$L(X|\omega,\theta) = \prod_{i=1}^{n} \sum_{k=1}^{K} \omega_k g_k(x_i|\theta_k)$$

Complete data likelihood

$$L(X|\omega, \theta, c) = \prod_{i=1}^{n} \prod_{k=1}^{K} [\omega_k g_k(x_i|\theta_k)]^{\mathbb{1}_{c_i=k}}$$

Probability of a data point x_i being generated by a component g_k

$$Pr(c_i = k | \omega, \theta) = \frac{\sum_{l} \omega_{l} g_{k}(x_i | \theta_k)}{\sum_{l} \omega_{l} g_{l}(x_i | \theta_l)} =: v_{i,k}(\omega, \theta)$$

Maximum likelihood framework

Bayesian framework

Model Fitting

Expectation-maximization algorithm

output: maximum likelihood estimates of ω and θ procedure:

 $\hat{\omega}, \hat{\theta} \leftarrow \text{initial values}$ repeat

 $\hat{\omega}, \hat{\theta} \leftarrow \operatorname{argmax}_{\omega,\theta} Q(\omega, \theta | \hat{\omega}, \hat{\theta})$ until convergence

where

$$\begin{aligned} Q(\omega, \theta | \hat{\omega}, \hat{\theta}) &= E_{c|X, \hat{\omega}, \hat{\theta}} \left[\log L(X | \omega, \theta, c) \right] \\ &= \sum_{i=1}^{n} \sum_{k=1}^{K} v_{i,k}(\hat{\omega}, \hat{\theta}) \left[\log \omega_k + \log g_k(x_i | \theta_k) \right] \end{aligned}$$

MCMC algorithm/Gibbs sampling

output: a sample from the posterior distribution $p(\omega, \theta, c|X)$

procedure:

set priors $p(\omega)$ and $p(\theta)$ on ω and θ

convenient: $(\omega_1, \ldots, \omega_K) \sim \text{Dirichlet}(a_1, \ldots, a_K)$

 $\omega \leftarrow \text{Dirichlet}(a_1^*, \dots, a_K^*),$

with $a_k^* = a_k - 1 + \sum_{i=1}^n \mathbb{1}_{c_i=k}$ $c_i \leftarrow p(c_i = k | \dots) = v_{i,k}(\omega, \theta)$

 $\theta_k \leftarrow p(\theta_k|\ldots) \propto \left[\prod_{\{i: c_i=k\}} g_k(x_i|\theta_k)\right] p_k(\theta_k)$

DETERMINING THE NUMBER OF COMPONENT

For each candidate model \mathcal{M} compute its Bayesian information criterion value

 $BIC(\mathcal{M}) = -2\log L(\hat{\eta}_{\mathcal{M}}) + r_{\mathcal{M}}\log n,$

where

 $L(\hat{\eta}_{\mathcal{M}}) = L(X|\hat{\omega}_{\mathcal{M}}, \hat{\theta}_{\mathcal{M}}),$

 $r_{\mathcal{M}}$ – # independent parameters in the model.

Select the model with the lowest BIC value.

With

K – upper bound on # components,

 K^* – best guess for actual # components \overline{K} ,

solve

 $K^* = \alpha \log \frac{n + \alpha - 1}{\alpha}$

for α .

Set the prior $p(\omega) \sim \text{Dirichlet}(\frac{\alpha}{K}, \dots, \frac{\alpha}{K})$.

Fit a model with K components.

Posterior distribution for \overline{K} obtained by counting the number of unique values assumed by indicators c_i per iteration of Gibbs sampling.

CLASSIFICATION WITH MIXTURE MODELS

Unsupervised: fit a model, classify as $c_i = \operatorname{argmax}_k v_{i,k}(\hat{\omega}, \theta)$

Semi-supervised: fit a model to the whole dataset, keeping $v_{i,k}$ constant on the training data; for the test data, classify as $c_i = \operatorname{argmax}_k v_{i,k}(\hat{\omega}, \hat{\theta})$

Supervised: estimate $\hat{\theta}_k$ by fitting g_k to training data from class k; set $\hat{\omega}_k = (\#\text{obs. in class } k)/n$; for the test data, classify as $c_i = \operatorname{argmax}_k v_{i,k}(\hat{\omega}, \hat{\theta})$